

Search Notes

Application/Control No.

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Examiner

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Applicant(s)/Patent under
Reexamination

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Art Unit

2816

SEARCHED

Class	Subclass	Date	Examiner
327	165,166, 170-176, 291-295, 297	1/31/2005	HLN
327	105,107	1/31/2005	HLN
327	141,144	1/31/2005	HLN
327	145	1/31/2005	HLN
326	93,96	1/31/2005	HLN

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
Search	Above	1/31/2005	HLN

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Shepardize Search	1/31/2005	HLN
EAST Text Search	1/31/2005	HLN